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**\*BIBDATASHEET\***

Bib Data Sheet

CONFIRMATION NO. 7027

SERIAL NUMBER 09/881,445	FILING DATE 06/13/2001  RULE	CLASS 438	GROUP ART UNIT 2818	ATTORNEY DOCKET NO. 4641-59261
<b>APPLICANTS</b>  Yoshijiro Ushio, Yokohama, JAPAN;  Takehiko Ueda, Tokyo, JAPAN;				
<b>** CONTINUING DATA *****</b> <i>Verified and</i> This application is a DIV of 09/316,082 05/20/1999 PAT 6,271,047				
<b>** FOREIGN APPLICATIONS *****</b> <i>Verified and</i> JAPAN 10-140292 05/21/1998 JAPAN 10-150963 06/01/1998 JAPAN 10-250071 09/03/1998 JAPAN 10-289175 10/12/1998 JAPAN 11-047485 02/25/1999				
<b>IF REQUIRED, FOREIGN FILING LICENSE GRANTED</b> <b>** 07/12/2001</b>				
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after met Verified and Acknowledged <i>M. M. M.</i> Examiner's Signature		STATE OR COUNTRY JAPAN	SHEETS DRAWING 10	TOTAL CLAIMS 16
				INDEPENDENT CLAIMS 3
<b>ADDRESS</b> KLARQUIST SPARKMAN CAMPBELL LEIGH & WHINSTON, LLP One World Trade Center, Suite 1600 121 S.W. Salmon Street Portland, OR 97204				
<b>TITLE</b> Layer-thickness detection methods and apparatus for wafers and the like, and polishing apparatus comprising same				